

## IN THE CLAIMS

1. (currently amended) A method for dew point measurement, comprising:  
feeding gas to be studied onto a cooled element with a condensation surface onto which a light flux is ~~directed~~ incident; and  
~~registering the~~ measuring the dew point from a value of reflection of the light flux reflected from the condensation surface, ~~advent of the dew point being determined on the basis of the registered value,~~  
characterized in that a the light flux is polarized in a plane of its the incidence ~~is used~~,  
and  
the an angle at which it is ~~directed onto the condensation surface of the cooled element of the incidence~~ is selected so that there is no reflection of the light flux in the absence of a condensate from the condensation surface ~~of the cooled element, which is the condensation surface being~~ made of a dielectric.
2. (original) The method according to claim 1, characterized in that the phase difference between beams reflected from the condensation surface of the cooled element and from the surface of a condensate film is additionally measured, thickness  $h$  of the condensate film on the condensation surface of the cooled element is determined, and the concentration of condensed admixtures in a predetermined volume of the studied gas is determined on the basis of the value of the thickness of the film formed during a certain period of time.

3. (currently amended) ~~★ In a~~ device for dew point measurement, comprising a housing equipped with a sampling tube, the housing containing a cooled element provided with a condensation surface and connected through an optical element to a radiator, the housing further containing a register, cooler and temperature sensor, ~~characterized in that~~ , the improvements wherein

the cooled element ~~provided with~~ has a condensation surface ~~is made in the form of a~~ dielectric plate,

the radiator ~~=in the form of~~ is a source of light polarized in ~~the~~ a plane of incidence thereof, ~~wherein the optical element is positioned in such a manner that the light flux of the source of polarized light is directed onto the condensation surface of the cooled element,~~ preferably at an angle, ~~the tangent of which is~~ about equal to the ~~refraction index~~ = Bruster angle of the condensation surface with condensate thereon.

4. (currently amended) The device according to claim 3, characterized in that the ~~direction of the polarized light flux onto the condensation surface of the cooled element is selected at an angle~~ is within the range of  $\pm 9^\circ$  of the ~~value of the~~ Bruster angle.

5. (original) The device according to claim 3, characterized in that it is provided with at least one additional register serving for measurement of scattered beams reflected from the surface of the formed condensate.

6. (currently amended) The device according to claim 3, characterized in that the ~~housing is equipped with a cooler and a temperature sensor, which are mounted on the a~~ sampling tube thereof.

7. (new) A method for dew point measurement, comprising feeding gas to be studied onto a cooled element with a condensation surface onto which a light flux is directed and registering the value of the light flux reflected from the condensation surface, advent of the dew point being determined on the basis of the registered value, wherein a light flux polarized in a plane of its incidence is used, and the angle at which it is directed onto the condensation surface of the cooled element is selected so that there is no reflection of the light flux in the absence of a condensate from the condensation surface of the cooled element, which is made of a dielectric, characterized in that the phase difference between beams reflected from the condensation surface of the cooled element and from the surface of a condensate film is additionally measured, thickness  $h$  of the condensate film on the condensation surface of the cooled element is determined, and the concentration of condensed admixtures in a predetermined volume of the studied gas is determined on the basis of the value of the thickness of the film formed during a certain period of time.

8. (new) A device for dew point measurement, comprising a housing equipped with a sampling tube, the housing containing a cooled element provided with a condensation surface and connected through an optical element to a radiator, the housing further containing a register, cooler and temperature sensor, characterized in that the cooled element provided with a condensation surface is made in the form of a dielectric plate, the radiator - in the form

of a source of light polarized in the plane of incidence thereof, wherein the optical element is positioned in such a manner that the light flux of the source of polarized light is directed onto the condensation surface of the cooled element, preferably at an angle within the range of  $\pm 9^\circ$  of the value of the Bruster angle, a register is made capable to measure the phase difference between beams reflected from the condensation surface of the cooled element and from the surface of a condensate film.

9. (new) The device according to claim 8, characterized in that it is provided with at least one additional register serving for measurement of scattered beams reflected from the surface of the formed condensate.

10. (new) The device according to claim 8, characterized in that the housing is equipped with a cooler and a temperature sensor, which are mounted on the sampling tube thereof.